Se	arch	Notes	

Application/Control No.	Applicant(s)/Patent und Reexamination	Applicant(s)/Patent under Reexamination	
10/056,080	SHIN-ICHIROU HARA	SHIN-ICHIROU HARASAWA	
Examiner	Art Unit		
Tran O Le	2633		

SEARCHED			
Class	Subclass	Date	Examiner
398	6,11,18	2/11/2005	TQL
ь	23,32,33	2/11/2005	TQL
n	37,38,62	2/11/2005	TQL
H	64,97,157	2/11/2005	TQL
и	160,177	2/11/2005	TQL
359	333-349	2/14/2005	TQL
372	70,71	2/16/2005	TQL
	82,83,88	2/16/2005	TQL
ABOVE UPDATED	Seapen	8/4/05	Þs

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
			<u> </u>
			7

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Jason C.	2/11/2005	TQL
Inventor check	2/11/2005	TQL
EAST (US-PEPUB; USPAT; EPO; TPO) See Search Results Printout	8/4/05	ð's .